# SN75LVDS32, SN75LVDS9637 HIGH-SPEED DIFFERENTIAL LINE RECEIVERS

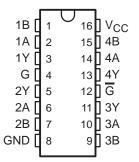
SLLS360B - JUNE 1999 - REVISED JUNE 2001

- Meets or Exceeds the Requirements of ANSI TIA/EIA-644 Standard
- Operates With a Single 3.3-V Supply
- Designed for Signaling Rate of up to 155 Mbps
- Differential Input Thresholds ±100 mV Max
- Low-Voltage TTL (LVTTL) Logic Output Levels
- Open-Circuit Fail Safe
- Characterized For Operation From 0°C to 70°C

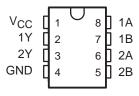
# description

The SN75LVDS32 and SN75LVDS9637 are differential line receivers that implement the electrical characteristics of low-voltage differential signaling (LVDS). This signaling technique lowers the output voltage levels of 5-V differential standard levels (such as EIA/TIA-422B) to reduce the power, increase the switching speeds, and

SN75LVDS32D (Marked as 75LVDS32) SN75LVDS32PW (Marked as DS32) (TOP VIEW)



SN75LVDS9637D (Marked as DF637 or 7L9637) SN75LVDS9637DGK (Marked as AXI) (TOP VIEW)



allow operation with a 3.3-V supply rail. Any of the four differential receivers provides a valid logical output state with a  $\pm 100$  mV allow operation with a differential input voltage within the input common-mode voltage range. The input common-mode voltage range allows 1 V of ground potential difference between two LVDS nodes.

The intended application of these devices and signaling technique is both point-to-point and multidrop (one driver and multiple receivers) data transmission over controlled impedance media of approximately  $100 \Omega$ . The transmission media may be printed-circuit board traces, backplanes, or cables. The ultimate rate and distance of data transfer is dependent upon the attenuation characteristics of the media and the noise coupling to the environment.

The SN75LVDS32 and SN75LVDS9637 are characterized for operation from 0°C to 70°C.

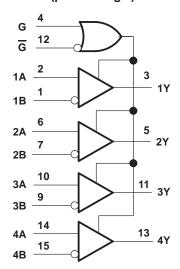


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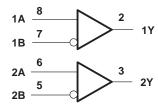


# logic diagram

#### 'LVDS32 logic diagram (positive logic)



## 'LVDS9637D logic diagram (positive logic)

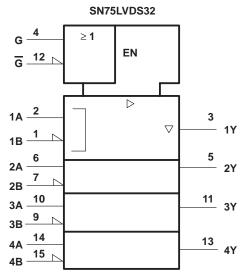


#### **Function Tables**

SN75LVDS32									
DIFFERENTIAL INPUT	ENA	BLES	OUTPUT						
A, B	G	G	Y						
V <sub>ID</sub> ≥ 100 mV	H X	X L	H H						
-100 mV < V <sub>ID</sub> < 100 mV	H X	X L	?						
V <sub>ID</sub> ≤ −100 mV	H X	X L	L L						
X	L	Н	Z						
Open	H X	X L	H H						

H = high level, L = low level, X = irrelevant, Z = high impedance (off), ? = indeterminate

# logic symbol†



<sup>†</sup> This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

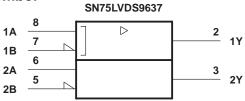
#### **Function Table**

#### SN75LVDS9637

DIFFERENTIAL INPUT	OUTPUT
A, B	Υ
V <sub>ID</sub> ≥ 100 mV	Н
-100 mV < V <sub>ID</sub> < 100 mV	?
$V_{ID} \le -100 \text{ mV}$	L
Open	Н

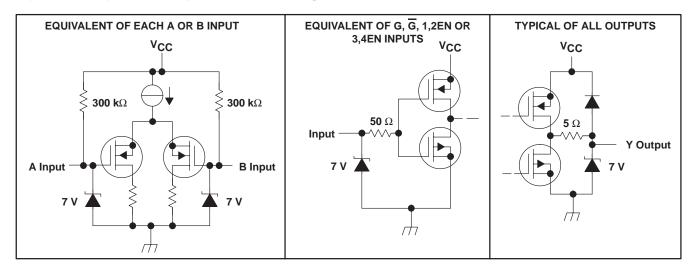
H = high level, L = low level, ? = indeterminate

# logic symbol†



†This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

## equivalent input and output schematic diagrams



# absolute maximum ratings over operating free-air temperature range (unless otherwise noted)†

Supply voltage range, V <sub>CC</sub> (see Note 1)	–0.5 V to 4 V
Input voltage range, V <sub>I</sub>	$-0.5 \text{ V}$ to $V_{CC} + 0.5 \text{ V}$
Input voltage range, V <sub>I</sub> (A or B)	
Continuous total power dissipation	See Dissipation Rating Table
Storage temperature range, T <sub>stg</sub>	65°C to 150°C
Lead temperature 1,6 mm (1/16 inch) from case for 10 seconds	260°C

<sup>†</sup> Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTE 1: All voltages, except differential I/O bus voltages, are with respect to the network ground terminal.

#### **DISSIPATION RATING TABLE**

PACKAGE	$T_{\mbox{\scriptsize A}} \le 25^{\circ}\mbox{\scriptsize C}$ POWER RATING	DERATING FACTOR <sup>‡</sup> ABOVE T <sub>A</sub> = 25°C	T <sub>A</sub> = 70°C POWER RATING	
D (8)	725 mW	464 mW		
D (16)	950 mW	7.6 mW/°C	608 mW	
PW	774 mW	6.2 mW/°C	496 mW	
DGK	425 mW	3.4 mW/°C	272 mW	

<sup>&</sup>lt;sup>‡</sup> This is the inverse of the junction-to-ambient thermal resistance when board mounted and with no air flow.

# recommended operating conditions

		MIN	NOM	MAX	UNIT
Supply voltage, V <sub>CC</sub>		3	3.3	3.6	V
High-level input voltage, V <sub>IH</sub>	G, <del>G</del>	2			V
Low-level input voltage, V <sub>IL</sub>	G, G			0.8	V
Magnitude of differential input voltage,  VID	Magnitude of differential input voltage,  VID				
Common-mode input voltage, V <sub>IC</sub> (see Figure 1)		$\frac{ V_{\text{ID}} }{2}$		$2.4-\frac{ V_{ID} }{2}$	V
				V <sub>CC</sub> – 0.8	V
Operating free-air temperature, TA		0		70	°C

# COMMON-MODE INPUT VOLTAGE RANGE

# DIFFERENTIAL INPUT VOLTAGE

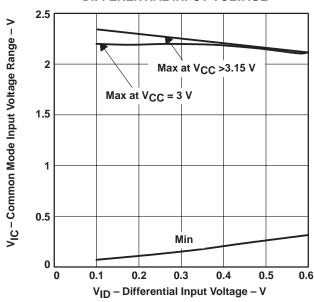


Figure 1.  $V_{\mbox{\scriptsize IC}}$  Versus  $V_{\mbox{\scriptsize ID}}$  and  $V_{\mbox{\scriptsize CC}}$ 

# SN75LVDSxxxx electrical characteristics over recommended operating conditions (unless otherwise noted)

	PARAMETER	TEST CO	TEST CONDITIONS		SN75LVDS32, SN75LVDS9637			
				MIN	TYP	MAX		
VITH+	Positive-going differential input voltage thresh	nold	See Figure 2	and Table 1			100	mV
VITH-	Negative-going differential input voltage thres	shold‡	See Figure 2 a	and lable i	-100	"		mV
Vон	High-level output voltage		$I_{OH} = -8 \text{ mA}$		2.4			V
VOL	Low-level output voltage		$I_{OL} = 8 \text{ mA}$				0.4	V
	Supply current	SN75LVDS32	Enabled,	No load		10	18	
ICC		3N73LVD332	Disabled			0.25	0.5	mA
		SN75LVDS9637	No load			5.5	10	
l	Input ourrent (A or P inpute)		V <sub>I</sub> = 0		-2	-10	-20	
'	Input current (A or B inputs)	nt (A or B inputs)			-1.2	-3		μΑ
I <sub>I</sub> (OFF)	Power-off input current (A or B inputs)		$V_{CC} = 0$ ,	V <sub>I</sub> = 3.6 V		6	20	μΑ
lн	H High-level input current (G, or G inputs)		V <sub>IH</sub> = 2 V				10	μΑ
IIL	Low-level input current (G, or G inputs)		V <sub>IL</sub> = 0.8 V				10	μΑ
loz	High-impedance output current		VO = 0 or $VCO$	C			±10	μΑ

<sup>&</sup>lt;sup>†</sup> All typical values are at  $T_A = 25^{\circ}$ C and with  $V_{CC} = 3.3 \text{ V}$ .

# SN75LVDSxxxx switching characteristics over recommended operating conditions (unless otherwise noted)

	PARAMETER	TEST CONDITIONS	SN' SN7	UNIT		
			MIN	TYP <sup>†</sup>	MAX	
t <sub>pLH</sub>	Propagation delay time, low-to-high-level output			2.1	6	ns
t <sub>pHL</sub>	Propagation delay time, high-to-low-level output			2.1	6	ns
t <sub>sk(p)</sub>	Pulse skew ( tpHL - tpLH )			0.6	1.5	ns
t <sub>sk(o)</sub>	Channel-to-channel output skew†	C <sub>L</sub> = 100 pF, See Figure 3		0.7	1.5	ns
t <sub>sk(pp)</sub> Part-to-part skew <sup>‡</sup>					0.6	ns
t <sub>r</sub>	Output signal rise time, 20% to 80%				0.6	ns
tf	Output signal fall time, 80% to 20%				1	ns
t <sub>pHZ</sub>	Propagation delay time, high-level-to-high-impedance output				25	ns
t <sub>pLZ</sub>	Propagation delay time, low-level-to-high-impedance output	Soo Eiguro 4			25	ns
to 7 Propagation delay time. low-level-to-high-impedance output		See Figure 4			25	ns
tpZL	Propagation delay time, high-impedance-to-low-level output				25	ns

<sup>&</sup>lt;sup>†</sup> All typical values are at 25°C and with a 3.3-V supply.



<sup>&</sup>lt;sup>‡</sup> The algebraic convention, in which the less positive (more negative) limit is designated minimum, is used in this data sheet for the negative-going differential input voltage threshold only.

 $<sup>\</sup>ddagger$   $t_{SK(p)}$  is the magnitude of the time difference between the high-to-low and low-to-high propagation delay times at an output

 $<sup>\</sup>S$   $t_{sk(0)}$  is the magnitude of the time difference between the outputs of a single device with all of their inputs connected together.

<sup>¶</sup> tsk(pp) is the magnitude of the difference in propagation delay times between any specified terminals of two devices when both devices operate with the same supply voltages, same temperature, and have identical packages and test circuits.

## PARAMETER MEASUREMENT INFORMATION

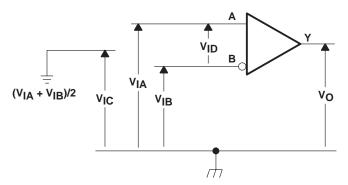
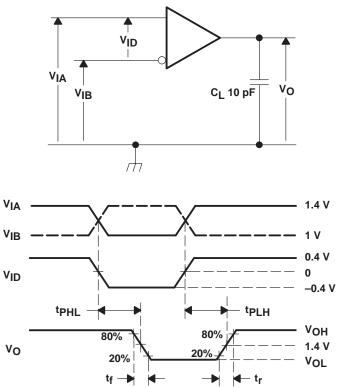


Figure 2. Voltage Definitions

Table 1. Receiver Minimum and Maximum Input Threshold Test Voltages

APPI VOLT		RESULTING DIFFERENTIAL INPUT VOLTAGE	RESULTING COMMON- MODE INPUT VOLTAGE		
VIA	V <sub>IB</sub>	$v_{ID}$	V <sub>IC</sub>		
1.25 V	1.15 V	100 mV	1.2 V		
1.15 V	1.25 V	−100 mV	1.2 V		
2.4 V	2.3 V	100 mV	2.35 V		
2.3 V	2.4 V	−100 mV	2.35 V		
0.1 V	0 V	100 mV	0.05 V		
0 V	0.1 V	–100 mV	0.05 V		
1.5 V	0.9 V	600 mV	1.2 V		
0.9 V	1.5 V	−600 mV	1.2 V		
2.4 V	1.8 V	600 mV	2.1 V		
1.8 V	2.4 V	−600 mV	2.1 V		
0.6 V	0 V	600 mV	0.3 V		
0 V 0.6 V		−600 mV	0.3 V		

#### PARAMETER MEASUREMENT INFORMATION

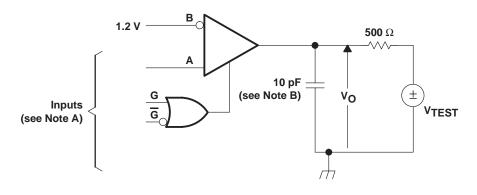


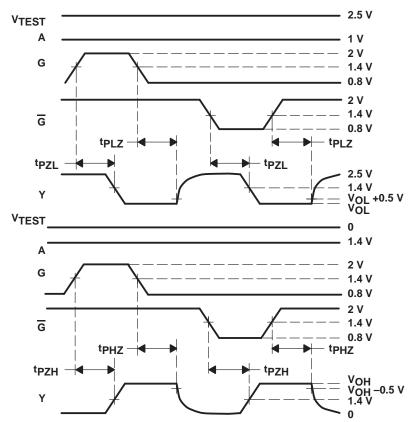
NOTES: A. All input pulses are supplied by a generator having the following characteristics:  $t_{\Gamma}$  or  $t_f \le 1$  ns, pulse repetition rate (PRR) = 50 Mpps, pulse width =  $10 \pm 0.2$  ns.

B. C<sub>L</sub> includes instrumentation and fixture capacitance within 6 mm of the D.U.T.

Figure 3. Timing Test Circuit and Wave Forms

#### PARAMETER MEASUREMENT INFORMATION





NOTES: A. All input pulses are supplied by a generator having the following characteristics:  $t_{\Gamma}$  or  $t_{f} \le 1$  ns, pulse repetition rate (PRR) = 0.5 Mpps, pulse width =  $500 \pm 10$  ns.

B.  $C_L$  includes instrumentation and fixture capacitance within 6 mm of the D.U.T.

Figure 4. Enable/Disable Time Test Circuit and Wave Forms

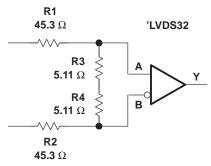
#### **APPLICATION INFORMATION**

#### using an LVDS receiver with RS-422 data

Receipt of data from a TIA/EIA-422 line driver may be accomplished using a TIA/EIA-644 line receiver with the addition of an attenuator circuit. This technique gives the user a very high-speed and low-power 422 receiver.

If the ground noise between the transmitter and receiver is not a concern (less than  $\pm 1$  V), the answer can be as simple as shown below in Figure 5. The use of a resistor divider circuit in front of the LVDS receiver attenuates the 422 differential signal to LVDS levels.

The resistors present a total differential load of  $100\,\Omega$  to match the characteristic impedance of the transmission line and to reduce the signal 10:1. The maximum 422 differential output signal or 6 V is reduced to 600 mV. The high input impedance of the LVDS receiver prevents input bias offsets and maintains a better than 200-mV differential input voltage threshold at the inputs to the divider. This circuit is used in front of each LVDS channel that also receives 422 signals.



NOTE A: The components used were standard values.

R1, R2 = NRC12F45R3TR, NIC Components, 45.3 Ohm, 1/8W, 1%, 1206 Package R3, R4 = NRC12F5R11TR, NIC Components, 5.11 Ohm, 1/8W, 1%, 1206 Package

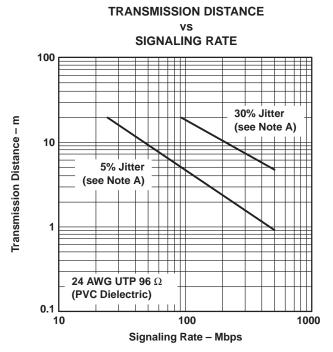
The resistor values do not need to be 1% tolerance. However, it can be difficult locating a supplier of resistors having values less than  $100~\Omega$  in stock and readily available. The user may find other suppliers with comparable parts having tolerances of 5% or even 10%. These parts are adequate for use in this circuit.

Figure 5. RS-422 Data Input to an LVDS Receiver Under Low Ground Noise Conditions

If ground noise between the RS-422 driver and LVDS receiver is a concern, then the common-mode voltage must be attenuated. The circuit must then be modified to connect the node between R3 and R4 to the LVDS receiver ground. This modification to the circuit increases the common-mode voltage from  $\pm 1$  V to greater than  $\pm 4.5$  V.

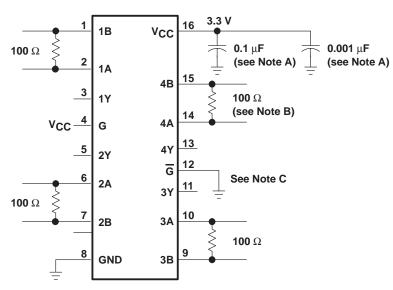
#### **APPLICATIONS INFORMATION**

The devices are generally used as building blocks for high-speed point-to-point data transmission where ground differences are less than 1 V. Devices can interoperate with RS-422, PECL, and IEEE-P1596. Drivers/receivers approach ECL speeds without the power and dual supply requirements.



NOTE A: This parameter is the percentage of distortion of the unit interval (UI) with a pseudorandom data pattern.

Figure 6. Typical Transmission Distance vs Signaling Rate



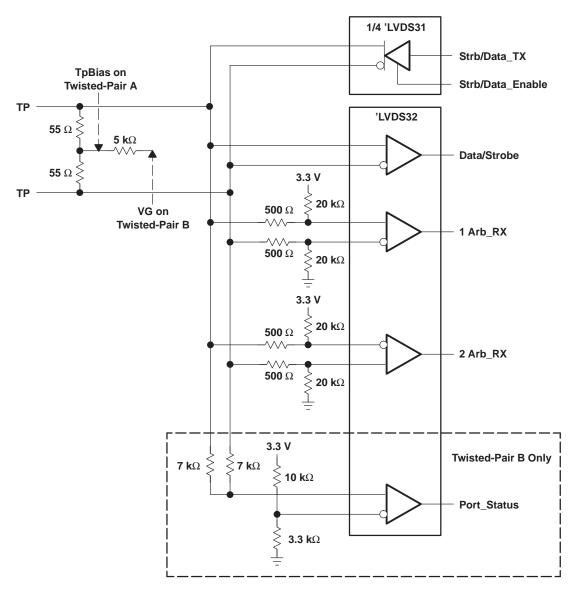
NOTES: A. Place a  $0.1 \,\mu\text{F}$  and a  $0.001 \,\mu\text{F}$  Z5U ceramic, mica or polystyrene dielectric, 0805 size, chip capacitor between V<sub>CC</sub> and the ground plane. The capacitors should be located as close as possible to the device terminals.

- B. The termination resistance value should match the nominal characteristic impedance of the transmission media with ±10%.
- C. Unused enable inputs should be tied to  $V_{\hbox{\footnotesize{CC}}}$  or GND as appropriate.

Figure 7. Typical Application Circuit Schematic



# **APPLICATION INFORMATION**



- NOTES: A. Resistors are leadless thick-film (0603) 5% tolerance.
  - B. Decoupling capacitance is not shown but recommended.
  - C. V<sub>CC</sub> is 3 V to 3.6 V.
  - D. The differential output voltage of the 'LVDS31 can exceed that allowed by IEEE1394.

Figure 8. 100-Mbps IEEE 1394 Transceiver

#### **APPLICATION INFORMATION**

#### fail safe

One of the most common problems with differential signaling applications is how the system responds when no differential voltage is present on the signal pair. The LVDS receiver is like most differential line receivers, in that its output logic state can be indeterminate when the differential input voltage is between –100 mV and 100 mV if it is within its recommended input common-mode voltage range. TI's LVDS receiver is different in how it handles the open-input circuit situation, however.

Open-circuit means that there is little or no input current to the receiver from the data line itself. This could be when the driver is in a high-impedance state or the cable is disconnected. When this occurs, the LVDS receiver will pull each line of the signal pair to near  $V_{CC}$  through 300-k $\Omega$  resistors as shown in Figure 9. The fail-safe feature uses an AND gate with input voltage thresholds at about 2.3 V to detect this condition and force the output to a high level, regardless of the differential input voltage.

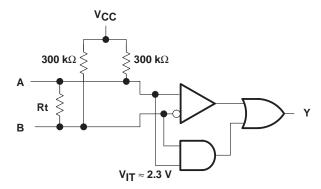
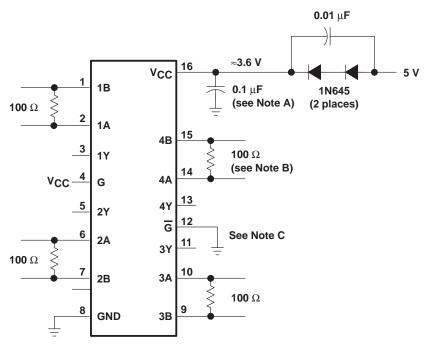


Figure 9. Open-Circuit Fail Safe of the LVDS Receiver

It is only under these conditions that the output of the receiver will be valid with less than a 100-mV differential input voltage magnitude. The presence of the termination resistor, Rt, does not affect the fail-safe function as long as it is connected as shown in the figure. Other termination circuits may allow a dc current to ground that could defeat the pullup currents from the receiver and the fail-safe feature.

#### **APPLICATION INFORMATION**



- NOTES: A. Place a 0.1 μF Z5U ceramic, mica or polystyrene dielectric, 0805 size, chip capacitor between V<sub>CC</sub> and the ground plane. The capacitor should be located as close as possible to the device terminals.
  - B. The termination resistance value should match the nominal characteristic impedance of the transmission media with ±10%.
  - C. Unused enable inputs should be tied to V<sub>CC</sub> or GND as appropriate.

Figure 10. Operation With 5-V Supply

#### related information

IBIS modeling is available for this device. Please contact the local TI sales office or the TI Web site at www.ti.com for more information.

For more application guidelines, please see the following documents:

- Low-Voltage Differential Signalling Design Notes (TI literature SLLA014)
- Interface Circuits for TIA/EIA-644 (LVDS) (TI literature SLLA038)
- Reducing EMI with LVDS (TI literature SLLA030)
- Slew Rate Control of LVDS Circuits (TI literature SLLA034)
- Using an LVDS Receiver with RS-422 Data (TI literature SLLA031)
- Evaluating the LVDS EVM (TI literature SLLA033)



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#### PACKAGING INFORMATION

Orderable part number	Status	Material type	Package   Pins	Package qty   Carrier	RoHS	Lead finish/	MSL rating/	Op temp (°C)	Part marking
	(1)	(2)			(3)	Ball material	Peak reflow		(6)
						(4)	(5)		
SN75LVDS32D	Active	Production	SOIC (D)   16	40   TUBE	Yes	NIPDAU	Level-1-260C-UNLIM	0 to 70	75LVDS32
SN75LVDS32D.B	Active	Production	SOIC (D)   16	40   TUBE	Yes	NIPDAU	Level-1-260C-UNLIM	0 to 70	75LVDS32
SN75LVDS32DR	Active	Production	SOIC (D)   16	2500   LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	0 to 70	75LVDS32
SN75LVDS32DR.B	Active	Production	SOIC (D)   16	2500   LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	0 to 70	75LVDS32
SN75LVDS9637D	Active	Production	SOIC (D)   8	75   TUBE	Yes	NIPDAU	Level-1-260C-UNLIM	0 to 70	DF637
SN75LVDS9637D.B	Active	Production	SOIC (D)   8	75   TUBE	Yes	NIPDAU	Level-1-260C-UNLIM	0 to 70	DF637

<sup>(1)</sup> Status: For more details on status, see our product life cycle.

Multiple part markings will be inside parentheses. Only one part marking contained in parentheses and separated by a "~" will appear on a part. If a line is indented then it is a continuation of the previous line and the two combined represent the entire part marking for that device.

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<sup>(3)</sup> RoHS values: Yes, No, RoHS Exempt. See the TI RoHS Statement for additional information and value definition.

<sup>(4)</sup> Lead finish/Ball material: Parts may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.

<sup>(5)</sup> MSL rating/Peak reflow: The moisture sensitivity level ratings and peak solder (reflow) temperatures. In the event that a part has multiple moisture sensitivity ratings, only the lowest level per JEDEC standards is shown. Refer to the shipping label for the actual reflow temperature that will be used to mount the part to the printed circuit board.

<sup>(6)</sup> Part marking: There may be an additional marking, which relates to the logo, the lot trace code information, or the environmental category of the part.

# PACKAGE OPTION ADDENDUM

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## OTHER QUALIFIED VERSIONS OF SN75LVDS32:

Military: SN55LVDS32

NOTE: Qualified Version Definitions:

• Military - QML certified for Military and Defense Applications

# **PACKAGE MATERIALS INFORMATION**

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## TAPE AND REEL INFORMATION





A0	Dimension designed to accommodate the component width
В0	Dimension designed to accommodate the component length
K0	Dimension designed to accommodate the component thickness
W	Overall width of the carrier tape
P1	Pitch between successive cavity centers

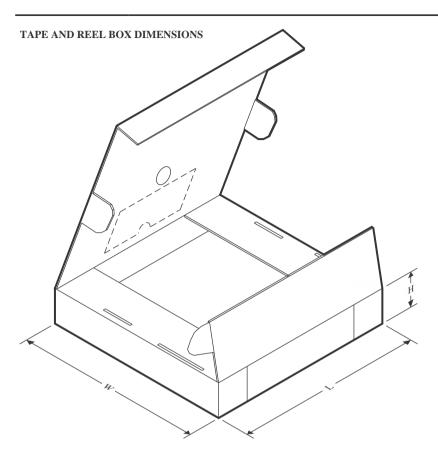
#### QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE



#### \*All dimensions are nominal

Device	Package Type	Package Drawing		SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
SN75LVDS32DR	SOIC	D	16	2500	330.0	16.4	6.5	10.3	2.1	8.0	16.0	Q1

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#### \*All dimensions are nominal

	Device	Device Package Type		Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
I	SN75LVDS32DR	SOIC	D	16	2500	340.5	336.1	32.0

# **PACKAGE MATERIALS INFORMATION**

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## **TUBE**



\*All dimensions are nominal

Device	Package Name	Package Type	Pins	SPQ	L (mm)	W (mm)	T (µm)	B (mm)
SN75LVDS32D	D	SOIC	16	40	507	8	3940	4.32
SN75LVDS32D.B	D	SOIC	16	40	507	8	3940	4.32
SN75LVDS9637D	D	SOIC	8	75	505.46	6.76	3810	4
SN75LVDS9637D	D	SOIC	8	75	507	8	3940	4.32
SN75LVDS9637D.B	D	SOIC	8	75	507	8	3940	4.32
SN75LVDS9637D.B	D	SOIC	8	75	505.46	6.76	3810	4

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